

# P-Channel Enhancement-Mode Vertical DMOS FETs

### **Ordering Information**

BV <sub>DSS</sub> /	R <sub>DS(ON)</sub>	I <sub>D(ON)</sub>	Ord	kage	
BV <sub>DGS</sub>	(max)	(min)	TO-92	TO-236AB*	Die <sup>†</sup>
-60V	12Ω	-0.5A	VP2106N3	_	_
-100V	12Ω	-0.5A	_	VP2110K1	VP2110ND

Product marking for SOT-23:

P1A\*

where \* = 2-week alpha date code

### **Features**

- □ Free from secondary breakdown
- Low power drive requirement
- Ease of paralleling
- Low C<sub>iss</sub> and fast switching speeds
- Excellent thermal stability
- Integral Source-Drain diode
- ☐ High input impedance and high gain
- Complementary N- and P-channel devices

### **Applications**

- Motor controls
- Converters
- Amplifiers
- Switches
- Power supply circuits
- Drivers (relays, hammers, solenoids, lamps, memories, displays, bipolar transistors, etc.)

## **Absolute Maximum Ratings**

Drain-to-Source Voltage	$BV_{DSS}$
Drain-to-Gate Voltage	$BV_{DGS}$
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

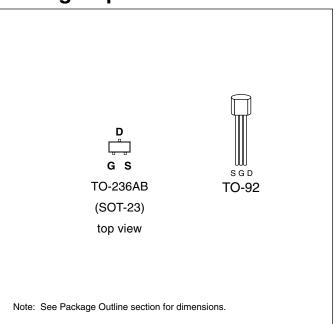
<sup>\*</sup> Distance of 1.6 mm from case for 10 seconds.

### **Advanced DMOS Technology**

These enhancement-mode (normally-off) transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

# **Package Options**



11/12/01

<sup>&</sup>lt;sup>†</sup>MIL visual screening available.

<sup>\*</sup>Same as SOT-23. All units shipped on 3,000 piece carrier tape reels.

### **Thermal Characteristics**

Package	I <sub>D</sub> (continuous)*	I <sub>D</sub> (pulsed)	Power Dissipation @ T <sub>A</sub> = 25°C	$^{ heta_{ m jc}}$ °C/W	$ heta_{\sf ja}$ $^{\circ}$ C/W	I <sub>DR</sub> *	I <sub>DRM</sub>
TO-236AB	-120mA	-400mA	0.36W	200	350	-120mA	-400mA
TO-92	-0.25A	-0.8A	0.74W	125	170	-0.25A	-0.8A

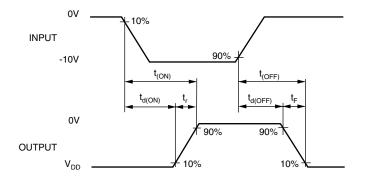
 $<sup>^{\</sup>star}$   $I_{D}$  (continuous) is limited by max rated  $T_{j\cdot}$ 

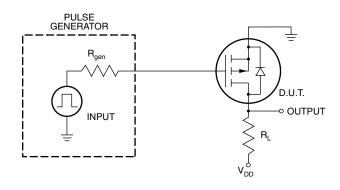
# Electrical Characteristics (@ 25°C unless otherwise specified)

Symbol	Parameter		Min	Тур	Max	Unit	Conditions	
BV <sub>DSS</sub>	Drain-to-Source	VP2110 -100	.,					
	Breakdown Voltage	VP2106	-60			V	$I_D = -1.0 \text{mA}, V_{GS} = 0 \text{V}$	
V <sub>GS(th)</sub>	Gate Threshold Voltage		-1.5		-3.5	V	$V_{GS} = V_{DS}$ , $I_D = -1.0$ mA	
$\Delta V_{GS(th)}$	Change in V <sub>GS(th)</sub> with Temperature			5.8	6.5	mV/°C	$I_D = -1.0$ mA, $V_{GS} = V_{DS}$	
I <sub>GSS</sub>	Gate Body Leakage			-1.0	-100	nA	$V_{GS} = \pm 20V$ , $V_{DS} = 0V$	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current				-10	μΑ	$V_{GS} = 0V$ , $V_{DS} = Max$ Rating	
					-1	mA	$V_{GS} = 0V$ , $V_{DS} = 0.8$ Max Rating $T_A = 125$ °C	
I <sub>D(ON)</sub>	ON-State Drain Current		-0.50	-1.0		Α	$V_{GS} = -10V, V_{DS} = -25V$	
R <sub>DS(ON)</sub>	Static Drain-to-Source	urce		11	15	Ω	$V_{GS} = -5V, I_{D} = -0.1A$	
	ON-State Resistance			9.0	12		$V_{GS} = -10V, I_D = -0.5A$	
$\Delta R_{DS(ON)}$	Change in R <sub>DS(ON)</sub> with Temperature			0.55	1.0	%/°C	$V_{GS} = -10V, I_D = -0.5A$	
G <sub>FS</sub>	Forward Transconductance		150	200		m&	$V_{DS} = -25V, I_{D} = -0.5A$	
C <sub>ISS</sub>	Input Capacitance			45	60			
C <sub>oss</sub>	Common Source Output Capacitance			22	30	pF	$V_{GS} = 0V, V_{DS} = -25V$ f = 1 MHz	
C <sub>RSS</sub>	Reverse Transfer Capacitance			3	8		1 = 1 WH 12	
t <sub>d(ON)</sub>	Turn-ON Delay Time			4	5			
t <sub>r</sub>	Rise Time Turn-OFF Delay Time			5	8	- ns	$V_{DD} = -25V$ $I_{D} = -0.5A$ $R_{GEN} = 25\Omega$	
t <sub>d(OFF)</sub>				5	9			
t <sub>f</sub>	Fall Time			4	8		GEN.	
V <sub>SD</sub>	Diode Forward Voltage Drop			-1.2	-2.0	V	$I_{SD} = -0.5A, V_{GS} = 0V$	
t <sub>rr</sub>	Reverse Recovery Time			400		ns	$I_{SD} = -0.5A, V_{GS} = 0V$	

#### Notes:

# **Switching Waveforms and Test Circuit**

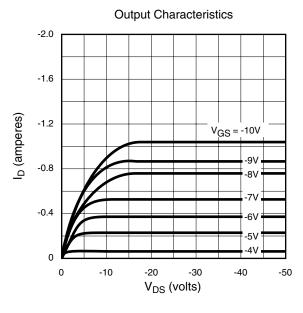


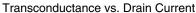


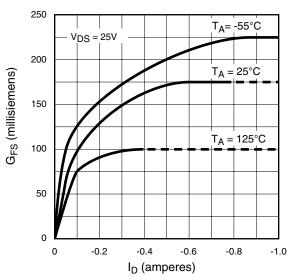
 $<sup>1.</sup> All\ D.C.\ parameters\ 100\%\ tested\ at\ 25^{\circ}C\ unless\ otherwise\ stated.\ (Pulse\ test:\ 300\mu s\ pulse,\ 2\%\ duty\ cycle.)$ 

<sup>2.</sup>All A.C. parameters sample tested.

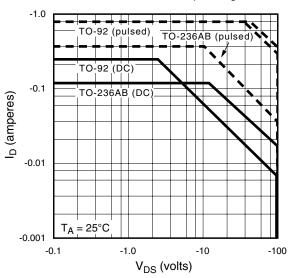
# **Typical Performance Curves**



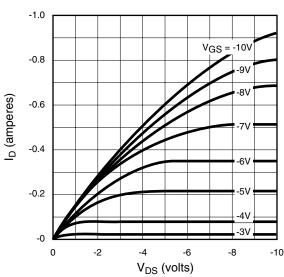




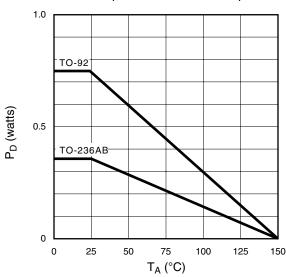
### Maximum Rated Safe Operating Area



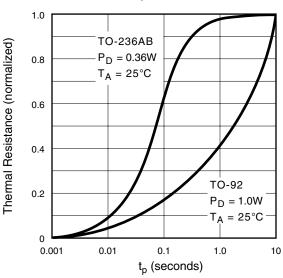
#### Saturation Characteristics



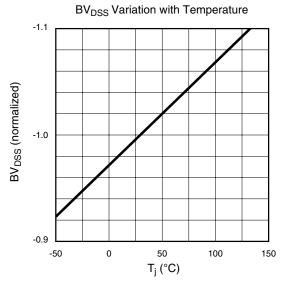
#### Power Dissipation vs. Ambient Temperature



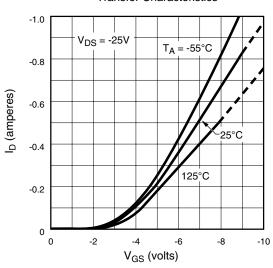
### Thermal Response Characteristics



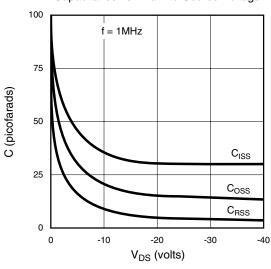
# **Typical Performance Curves**



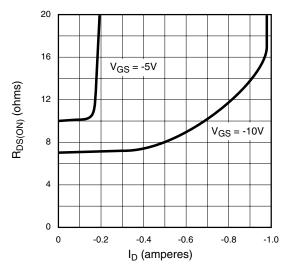




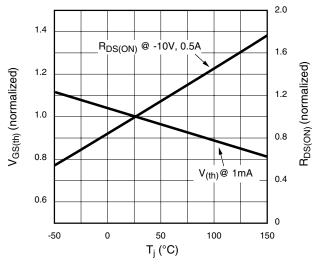
### Capacitance vs. Drain-to-Source Voltage



#### On-Resistance vs. Drain Current



 $V_{(th)}$  and  $R_{DS}$  Variation with Temperature



Gate Drive Dynamic Characteristics

